

**Correlation between the UV-reflectance spectra and the structure of poly-Si films obtained by aluminium induced crystallization**

Dimova-Malinovska, D.; Angelov, O.; Sendova-Vassileva, M.; **Mikli, Valdek** Journal of optoelectronics and advanced materials 2009 / 9, p. 1079-1085 [https://www.researchgate.net/publication/288122478\\_Correlation\\_between\\_the\\_UV-reflectance\\_spectra\\_and\\_the\\_structure\\_of\\_poly-Si\\_films\\_obtained\\_by\\_Aluminium\\_Induced\\_Crystallization](https://www.researchgate.net/publication/288122478_Correlation_between_the_UV-reflectance_spectra_and_the_structure_of_poly-Si_films_obtained_by_Aluminium_Induced_Crystallization)

**Influence of differently formed interfacial aluminium oxide on the structural properties of poly-Si films prepared by aluminium induced crystallisation**

Dimova-Malinovska, D.; Nichev, H.; Angelov, O.; Sendova-Vassileva, M.; Sendova, M.; **Mikli, Valdek** Journal of optoelectronics and advanced materials 2007 / 2, p. 359-362

**Room temperature sensitivity of Ta doped nanocrystalline ZnO films to NH<sub>3</sub> exposure**

Nichev, H.; Angelov, O.; Kamenova, M.; **Mikli, Valdek**; Dimova-Malinovska, D. Journal of optoelectronics and advanced materials 2009 / 10, p. 1371-1374

[https://www.researchgate.net/publication/290261533\\_Room\\_temperature\\_sensitivity\\_of\\_Ta\\_doped\\_nanocrystalline\\_ZnO\\_films\\_to\\_NH3\\_exposure](https://www.researchgate.net/publication/290261533_Room_temperature_sensitivity_of_Ta_doped_nanocrystalline_ZnO_films_to_NH3_exposure)

**Sensitivity of ZnO films doped with Er, Ta and Co to NH<sub>3</sub> at room temperature**

Dimova-Malinovska, D.; Nichev, H.; Georgieva, V.; Angelov, O.; Pivin, J.-C.; **Mikli, Valdek** Physica status solidi (a) : applications and materials science 2008 / 8, p. 1993-1997 : ill [https://link.springer.com/chapter/10.1007/978-1-4020-9916-8\\_32](https://link.springer.com/chapter/10.1007/978-1-4020-9916-8_32)